



INTEGRATED ELECTROMIGRATION LENGTH EFFECT
TESTING METHOD AND APPARATUS
Inventor: Wei Zhang Application No. 10/082,431 Docket: SUNMP308

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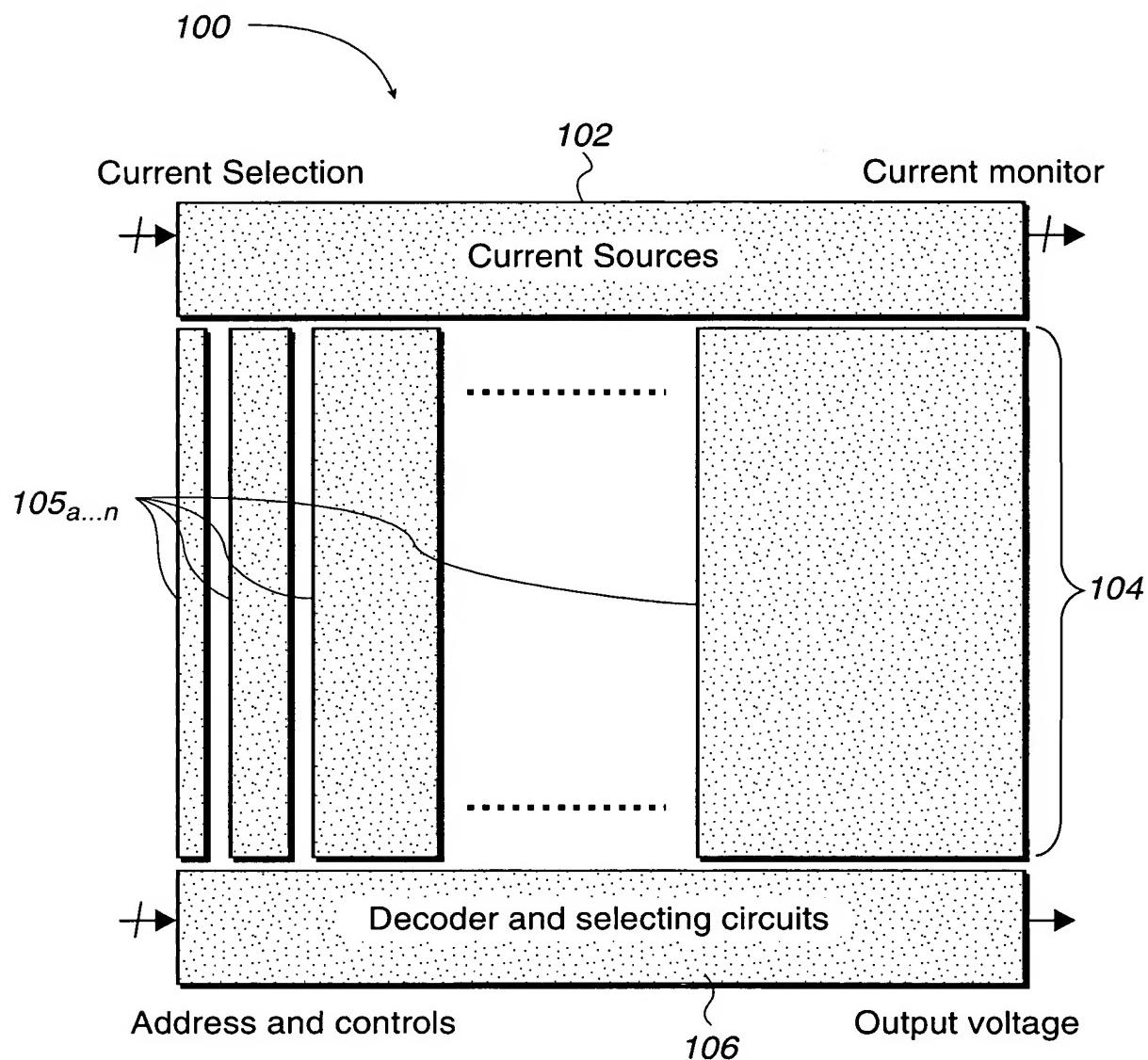


Fig. 1A



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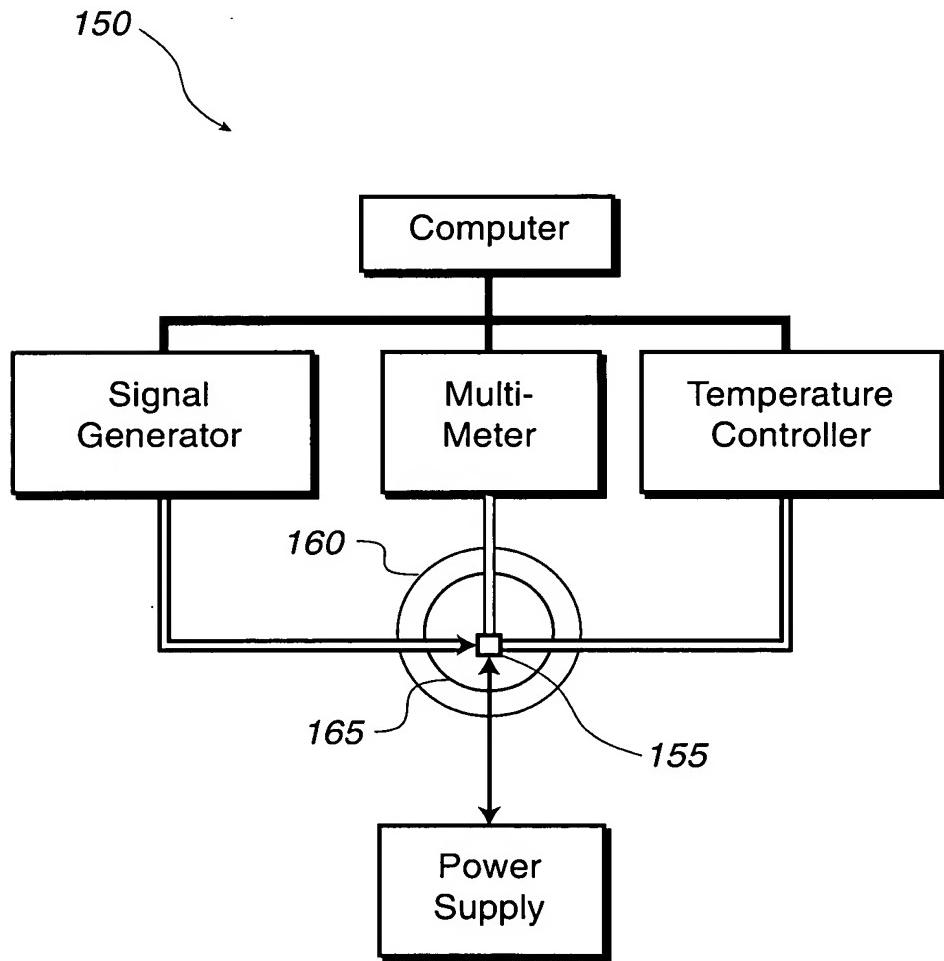


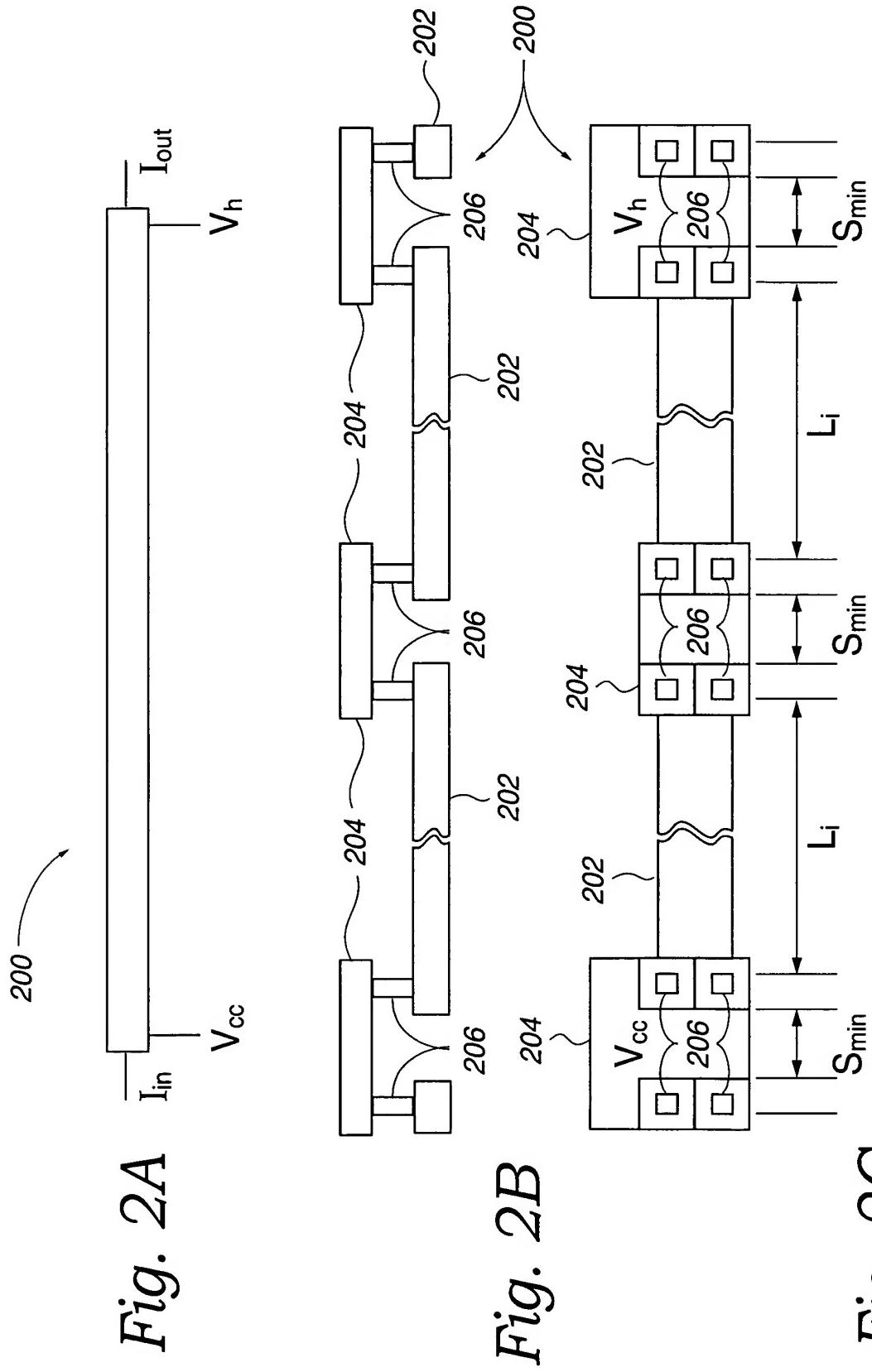
Fig. 1B



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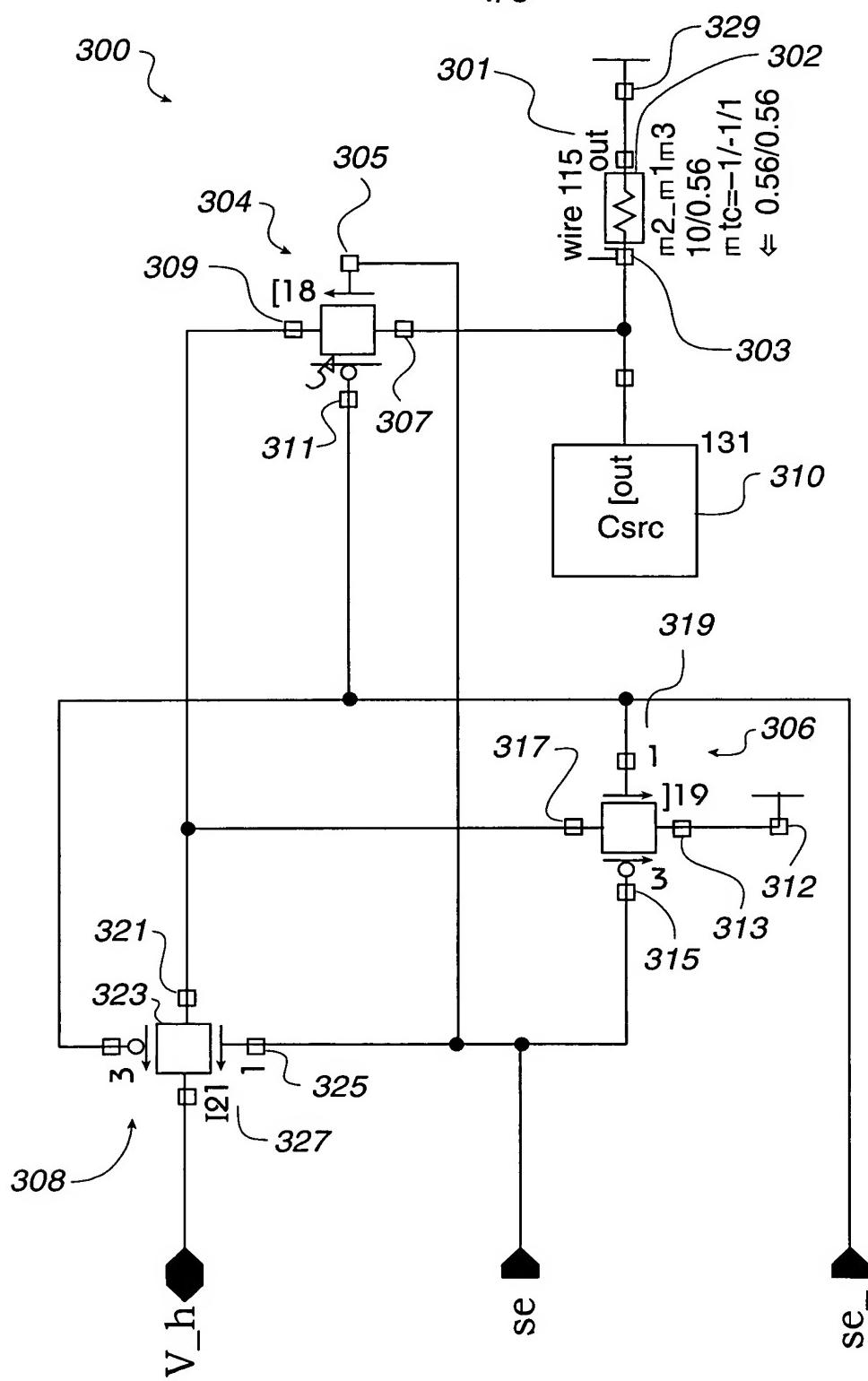


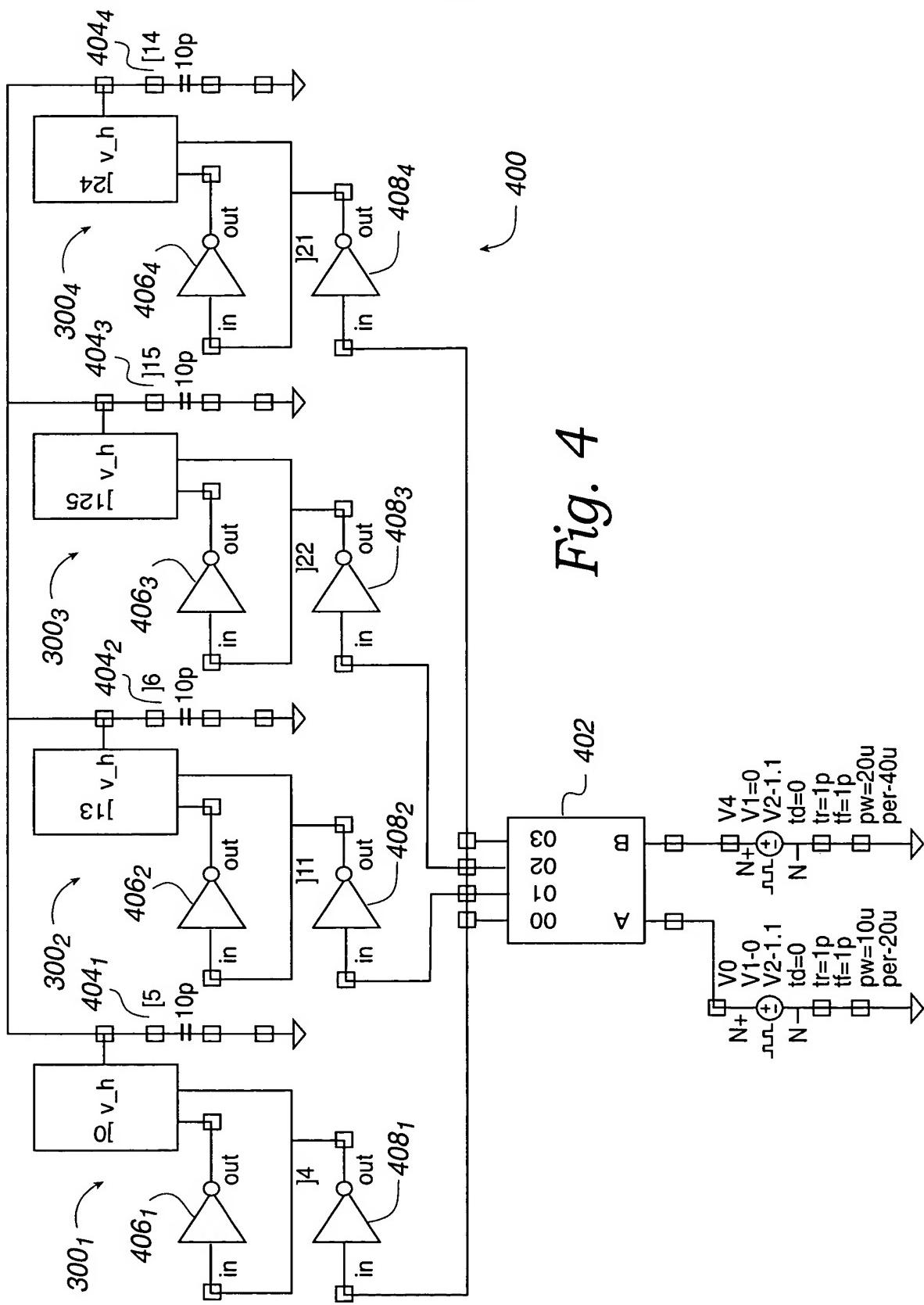
Fig. 3



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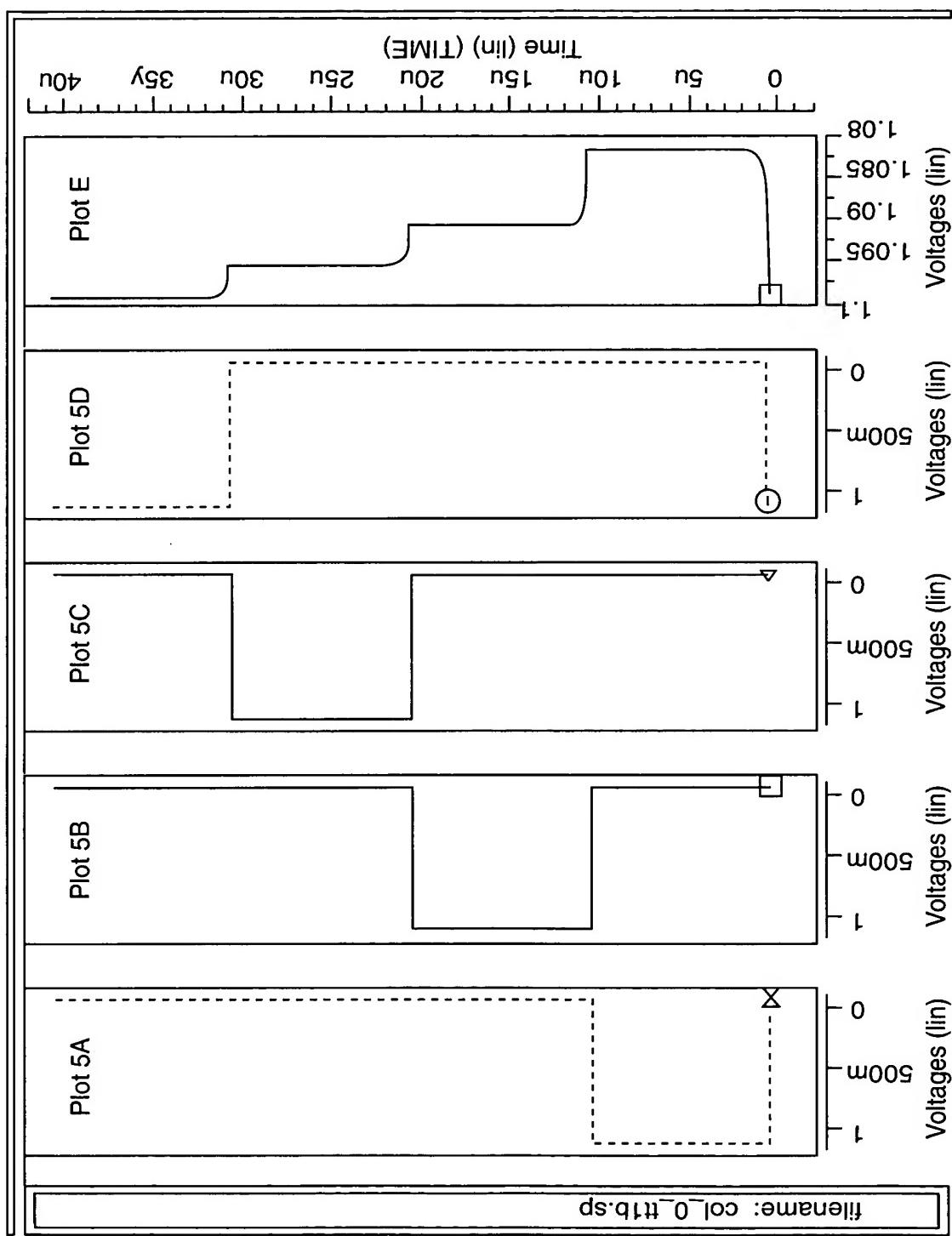


Fig. 5



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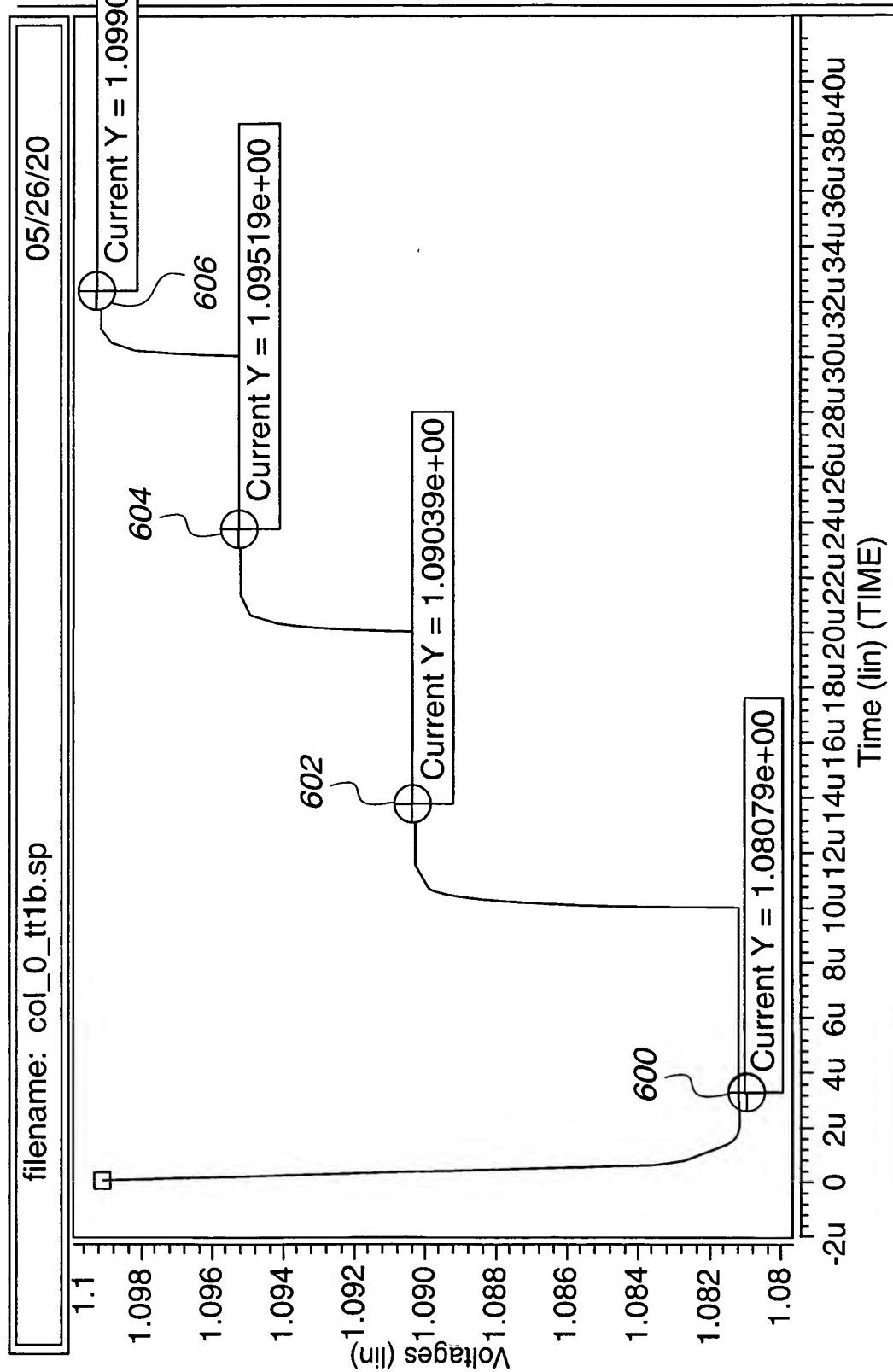


Fig. 6



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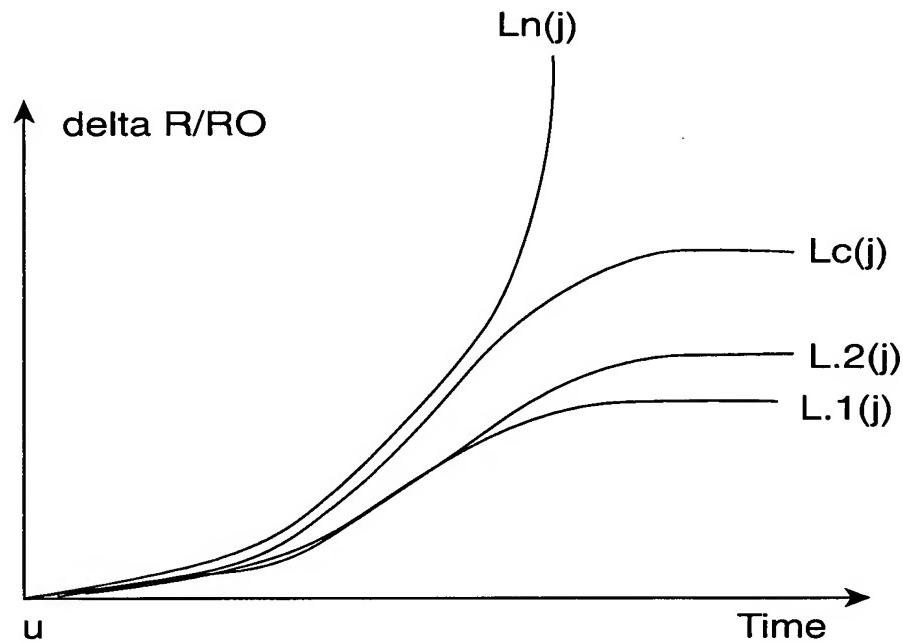


Fig. 7

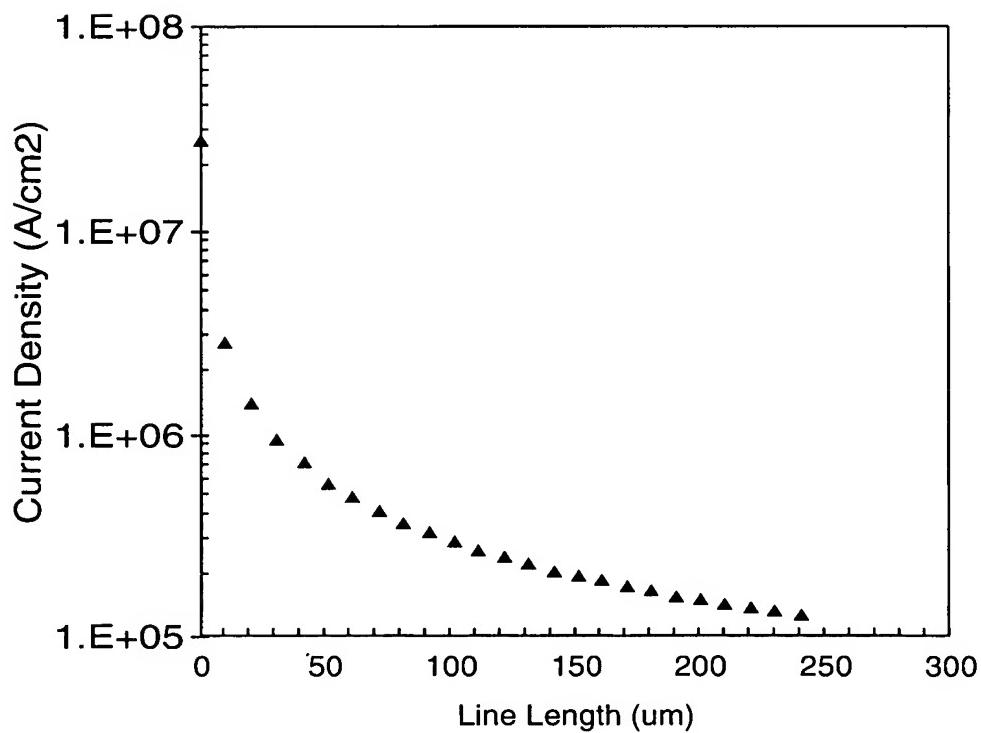


Fig. 8



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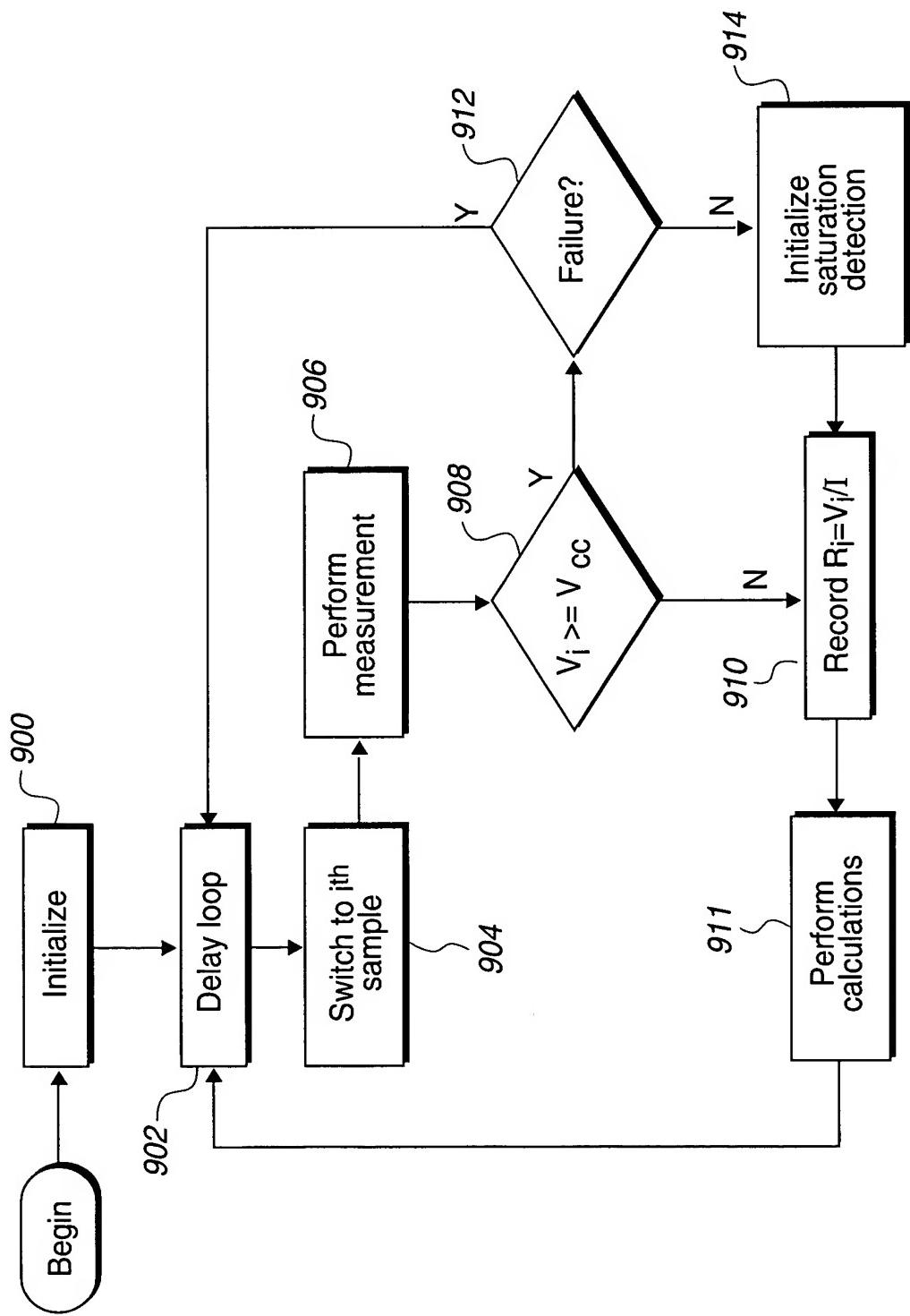


Fig. 9